

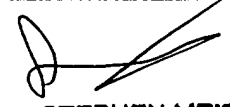
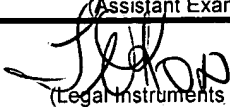


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/758,128	LEE, YONG-DUK	
	Examiner	Art Unit	
	Rene Garcia, Jr.	2853	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
347		16			347	19				
INTERNATIONAL CLASSIFICATION										
B	4	1	J	29/38						
B	4	1	J	29/393						
				/						
				/						
				/						

**STEPHEN MEIER**  
**SUPERVISORY PATENT EXAMINER**

 Rene Garcia Jr (Assistant Examiner) (Date)		 <b>STEPHEN MEIER</b> <b>SUPERVISORY PATENT EXAMINER</b> (P Primary Examiner) (Date)		Total Claims Allowed: 40	
 (Legal Instruments Examiner) (Date)				O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant						<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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